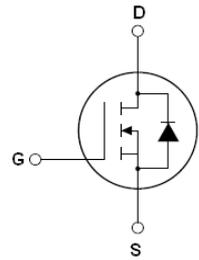


Features:

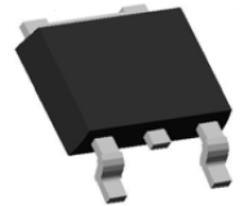
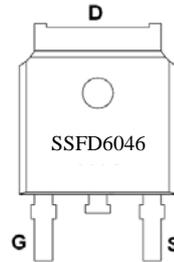
- Advanced trench process technology
- avalanche energy, 100% test
- Fully characterized avalanche voltage and current

ID =12A
BV=60V
Rdson=50mΩ (max.)



Description:

The SSFD6046 is a new generation of middle voltage N-Channel enhancement mode trench power MOSFET. This new technology increases the device reliability and electrical parameter repeatability. SSFD6046 is assembled in high reliability and qualified assembly house.



TOP View (TO252)

Marking and pin Assignment

Absolute Maximum Ratings

| | Parameter | Max. | Units |
|-----------------------------|--|-------------|-------|
| $I_D@T_c=25^\circ\text{C}$ | Continuous drain current, VGS@10V | 12 | A |
| $I_D@T_c=100^\circ\text{C}$ | Continuous drain current, VGS@10V | 9 | |
| I_{DM} | Pulsed drain current ① | 30 | |
| $P_D@T_c=25^\circ\text{C}$ | Power dissipation | 20 | W |
| | Linear derating factor | 0.12 | W/°C |
| V_{GS} | Gate-to-Source voltage | ±20 | V |
| E_{AS} | Single pulse avalanche energy ② | 8 | mJ |
| E_{AR} | Repetitive avalanche energy | TBD | |
| T_J T_{STG} | Operating Junction and Storage Temperature Range | -55 to +175 | °C |

Thermal Resistance

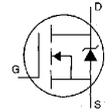
| | Parameter | Min. | Typ. | Max. | Units |
|-----------------|---------------------|------|------|------|-------|
| $R_{\theta JC}$ | Junction-to-case | — | — | 7.5 | °C/W |
| $R_{\theta JA}$ | Junction-to-ambient | — | — | 60 | |

Electrical Characteristics @T_J=25 °C (unless otherwise specified)

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------------|--------------------------------------|------|------|------|-------|---|
| BV_{DSS} | Drain-to-Source breakdown voltage | 60 | — | — | V | $V_{GS}=0V, I_D=250\mu A$ |
| $R_{DS(on)}$ | Static Drain-to-Source on-resistance | — | 46 | 50 | mΩ | $V_{GS}=10V, I_D=12A$ |
| $V_{GS(th)}$ | Gate threshold voltage | 1.0 | — | 3.0 | V | $V_{DS}=V_{GS}, I_D=250\mu A$ |
| g_{fs} | Forward transconductance | — | 15 | — | S | $V_{DS}=5V, I_D=12A$ |
| I_{DSS} | Drain-to-Source leakage current | — | — | 1 | μA | $V_{DS}=60V, V_{GS}=0V$ |
| | | — | — | 10 | | $V_{DS}=60V, V_{GS}=0V, T_J=55^\circ\text{C}$ |
| I_{GSS} | Gate-to-Source forward leakage | — | — | 100 | nA | $V_{GS}=20V$ |
| | Gate-to-Source reverse leakage | — | — | -100 | | $V_{GS}=-20V$ |

| | | | | | | |
|--------------|--------------------------------|---|-----|---|----|--|
| Q_g | Total gate charge | — | 7.5 | — | nC | $I_D=12A$ $V_{DD}=30V$ $V_{GS}=10V$ |
| Q_{gs} | Gate-to-Source charge | — | 1.2 | — | | |
| Q_{gd} | Gate-to-Drain("Miller") charge | — | 2 | — | | |
| $t_{d(on)}$ | Turn-on delay time | — | 4.5 | — | nS | $V_{DD}=30V$ $I_D=2A, R_L=2.5\Omega$ $R_G=3\Omega$ $V_{GS}=10V$ |
| t_r | Rise time | — | 3.5 | — | | |
| $t_{d(off)}$ | Turn-Off delay time | — | 16 | — | | |
| t_f | Fall time | — | 2 | — | | |
| C_{iss} | Input capacitance | — | 450 | — | pF | $V_{GS}=0V$ $V_{DS}=30V$ $f=1.0MHZ$ |
| C_{oss} | Output capacitance | — | 60 | — | | |
| C_{rss} | Reverse transfer capacitance | — | 25 | — | | |

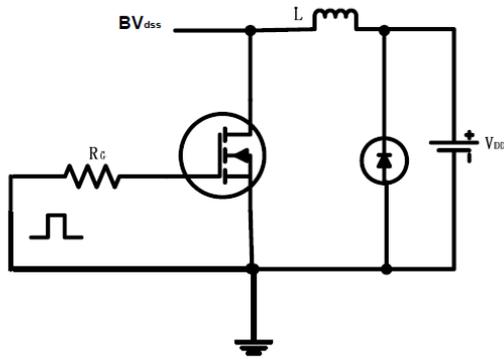
Source-Drain Ratings and Characteristics

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|----------|---|---|------|------|-------|---|
| I_S | Continuous Source Current (Body Diode) | — | — | 12 | A | MOSFET symbol showing the integral reverse p-n junction diode.  |
| I_{SM} | Pulsed Source Current (Body Diode) ① | — | — | 30 | | |
| V_{SD} | Diode Forward Voltage | — | — | 1 | V | $T_J=25^\circ C, I_S=1A, V_{GS}=0V$ ③ |
| t_{rr} | Reverse Recovery Time | — | 25 | — | nS | $T_J=25^\circ C, I_F=12A$ $di/dt=100A/\mu s$ ③ |
| Q_{rr} | Reverse Recovery Charge | — | 30 | — | nC | |
| t_{on} | Forward Turn-on Time | Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$) | | | | |

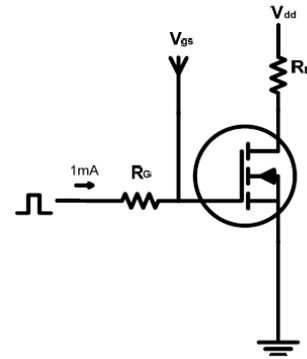
Notes:

- ① Repetitive rating; pulse width limited by max junction temperature.
- ② Test condition: $L = 0.1mH, V_{DD} = 40V, I_D = 10A$
- ③ Pulse width $\leq 300\mu s$, duty cycle $\leq 1.5\%$; $R_G = 25\Omega$ Starting $T_J = 25^\circ C$

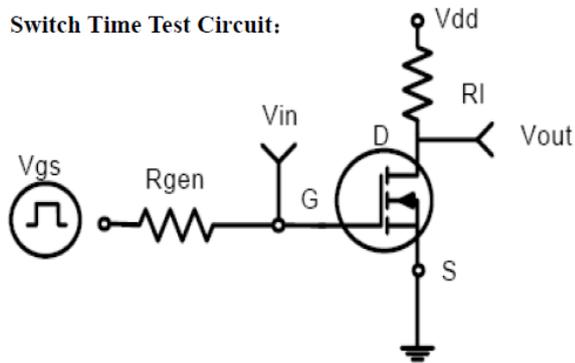
EAS test circuits:



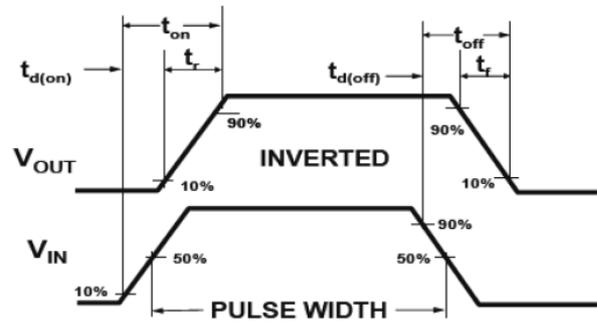
Gate charge test circuit:



Switch Time Test Circuit:



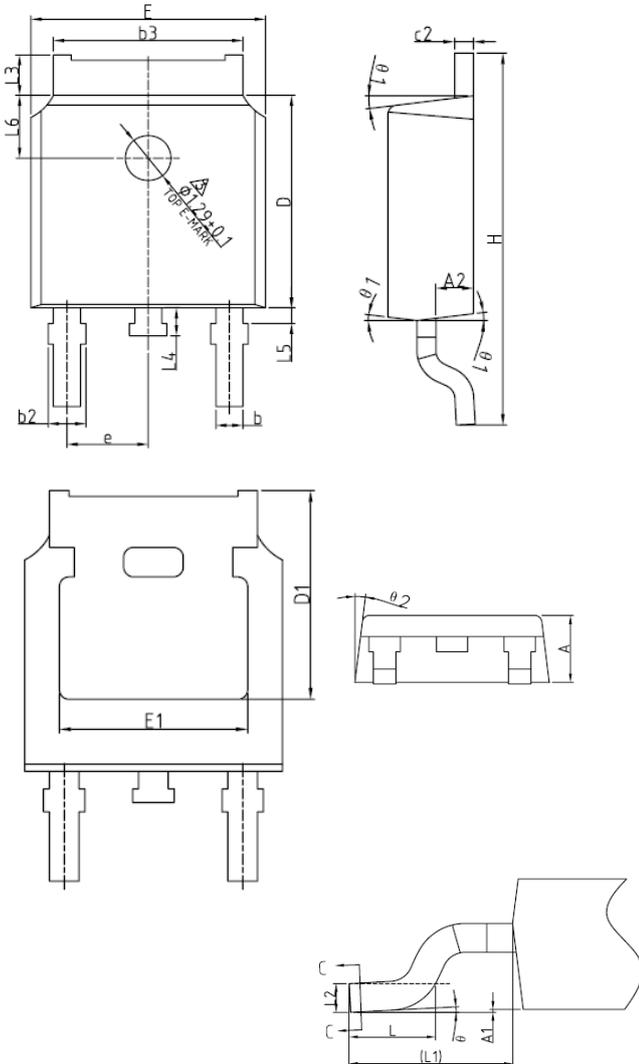
Switch Waveforms:



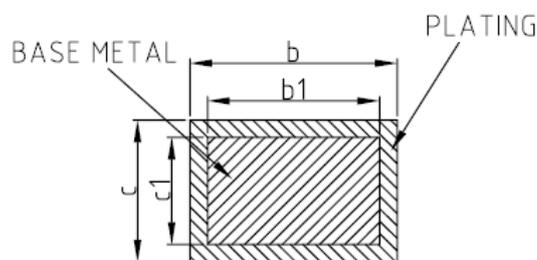
Mechanical Data:

TO-252E-2-M PACKAGE INFORMATION

Dimensions in Millimeters



| SYMBOL | MIN | NOM | MAX |
|--------|---------|-------|-------|
| A | 2.20 | 2.30 | 2.38 |
| A1 | 0 | — | 0.10 |
| A2 | 0.90 | 1.01 | 1.10 |
| b | 0.72 | — | 0.85 |
| b1 | 0.71 | 0.76 | 0.81 |
| b2 | 0.72 | — | 0.90 |
| b3 | 5.13 | 5.33 | 5.46 |
| c | 0.47 | — | 0.60 |
| c1 | 0.46 | 0.51 | 0.56 |
| c2 | 0.47 | — | 0.60 |
| D | 6.00 | 6.10 | 6.20 |
| D1 | 5.25 | — | — |
| E | 6.50 | 6.60 | 6.70 |
| E1 | 4.70 | — | — |
| e | 2.186 | 2.286 | 2.386 |
| H | 9.80 | 10.10 | 10.40 |
| L | 1.40 | 1.50 | 1.70 |
| L1 | 2.90REF | | |
| L2 | 0.51BSC | | |
| L3 | 0.90 | — | 1.25 |
| L4 | 0.60 | 0.80 | 1.00 |
| L5 | 0.15 | — | 0.75 |
| L6 | 1.80REF | | |
| θ | 0° | — | 8° |
| θ 1 | 5° | 7° | 9° |
| θ 2 | 5° | 7° | 9° |



NOTES:

1. Dimensions are inclusive of plating
2. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils.
3. Dimension L is measured in gauge plane.
4. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.